

Sample &

Buy



DS150DF1610

SNLS490-NOVEMBER 2014

# DS150DF1610 12.5 to 15 Gbps 16-Channel Retimer

Technical

Documents

# 1 Features

- Pin-Compatible Family
  - DS150DF1610: 12.5 to 15G
  - DS125DF1610: 9.8 to 12.5G
  - DS110DF1610: 8.5 to 11.3G
- Fully Adaptive CTLE
- Self tuning DFE, with Optional Continuous Adaption
- Configurable VGA
- Adjustable Transmit V<sub>OD</sub>
- Adjustable 3-tap Transmit FIR Filter
- On-chip AC Coupling on Receive Inputs
- Locks to Half/Quarter/Eighth Data Rates for Legacy Support
- On-chip Eye Monitor(EOM), PRBS Checker, Pattern Generator
- Supports JTAG Boundary Scan
- Programmable Output Polarity Inversion
- Input Signal Detection, CDR Lock Detection
- Single 2.5 V ±5% Power Supply
- SMBus Based Register Configuration
- Optional EEPROM Configuration
- 15 mm x 15 mm, 196-pin FCBGA Package
- Operating Temp Range : -10°C to +85°C

# 2 Applications

• Backplane/Midplane reach extension

# 3 Description

Tools &

Software

The DS150DF1610 is a sixteen-channel multi-rate retimer with integrated signal conditioning features. The device includes a fully adaptive Continuous Time Linear Equalizer (CTLE), Decision Feedback Equalizer (DFE), clock and data recovery (CDR), and a transmit FIR filter to enhance the reach and robustness over long, lossy, crosstalk impaired high speed serial links to achieve BER <  $1 \times 10^{-15}$ .

Support &

Community

**.**...

Each channel of the DS150DF1610 independently locks to serial data rates between 12.5 and 15 Gbps plus the divide by 2, 4 and 8 sub-multiples. A simple external oscillator (±100ppm) that is synchronous or asynchronous with the incoming data stream is used as a calibration clock.

A programmable transmit Finite Impulse Response (FIR) filter offers control of the pre-cursor, main tap and post-cursor for transmit equalization. The fully adaptive receive equalization (CTLE and DFE) enables longer distance transmission in lossy copper interconnects and backplanes with multiple connectors.

A non-disruptive mission mode eye-monitor feature allows link monitoring internal to the receiver. The built-in PRBS generator and checker compliment the internal diagnostic features to complete standalone BERT measurements. Built-in JTAG enables manufacturing tests.

To download the full datasheet, please send a request to: highspeed\_datasheets@list.ti.com

# Device Information<sup>(1)</sup> PART NUMBER PACKAGE BODY SIZE NOM 0450054000 50000 (400) 4500 mm u 45

DS150DF1610FCBGA (196)15.00 mm x 15.00 mm(1) For all available packages, see the orderable addendum at





## 4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	COMMENTS
November 2014	*	Initial Release

## 5 Device and Documentation Support

#### 5.1 Trademarks

All trademarks are the property of their respective owners.

#### 5.2 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 5.3 Glossary

#### SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 6 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designed devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

## IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2025, Texas Instruments Incorporated